



ALPHA & OMEGA
SEMICONDUCTOR

AOD409G
60V P-Channel MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{DS(ON)}$
- Logic Level Driving
- RoHS and Halogen-Free Compliant

Product Summary

V_{DS}	-60V
I_D (at $V_{GS}=-10V$)	-28A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 40mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 55mΩ

Applications

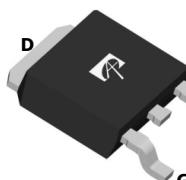
- Industrial and Motor Drive applications

100% UIS Tested
100% R_g Tested

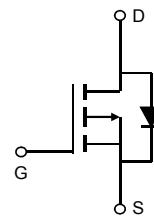
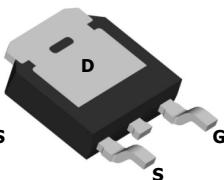


TO252
DPAK

Top View



Bottom View



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOD409G	TO-252	Tape & Reel	2500

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	-28	A
		-18	
Pulsed Drain Current ^C	I_{DM}	-80	
Continuous Drain Current	I_{DSM}	-9	A
		-7	
Avalanche Current ^C	I_{AS}	-26	A
Avalanche energy $L=0.1\text{mH}$ ^C	E_{AS}	34	mJ
Power Dissipation ^B	P_D	60	W
		24	
Power Dissipation ^A	P_{DSM}	6.2	W
		4.0	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	15	20	°C/W
		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.7	2.1	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.5	-2.0	-2.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-20\text{A}$ $T_J=125^\circ\text{C}$		33 56	40 68	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-20\text{A}$		44	55	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-20\text{A}$		33		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-28	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-30\text{V}, f=1\text{MHz}$		2350		pF
C_{oss}	Output Capacitance			160		pF
C_{rss}	Reverse Transfer Capacitance			115		pF
R_g	Gate resistance	$f=1\text{MHz}$		2.0	4.0	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-30\text{V}, I_D=-20\text{A}$		45	65	nC
$Q_g(4.5\text{V})$	Total Gate Charge			22	33	nC
Q_{gs}	Gate Source Charge			7		nC
Q_{gd}	Gate Drain Charge			10		nC
Q_{oss}	Output Charge	$V_{GS}=0\text{V}, V_{DS}=-30\text{V}$		8		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-30\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		10		ns
t_r	Turn-On Rise Time			6		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			47		ns
t_f	Turn-Off Fall Time			12		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-20\text{A}, di/dt=500\text{A}/\mu\text{s}$		23		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-20\text{A}, di/dt=500\text{A}/\mu\text{s}$		107		nC

A. The value of R_{0JA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The Power dissipation P_{DSM} is based on $R_{0JA} \leq 10\text{s}$ and the maximum allowed junction temperature of 150° C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$.

D. The R_{0JA} is the sum of the thermal impedance from junction to case R_{0JC} and case to ambient.

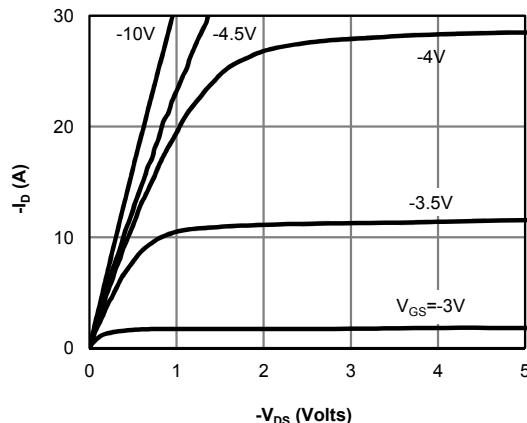
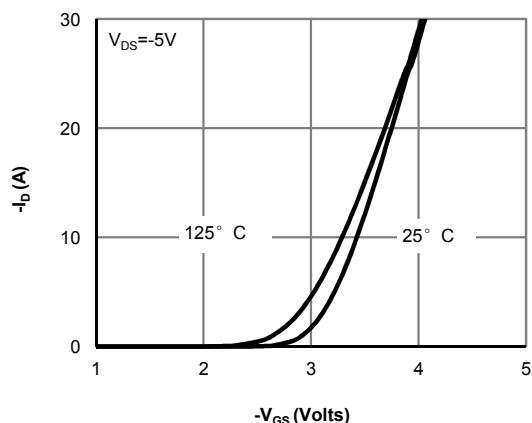
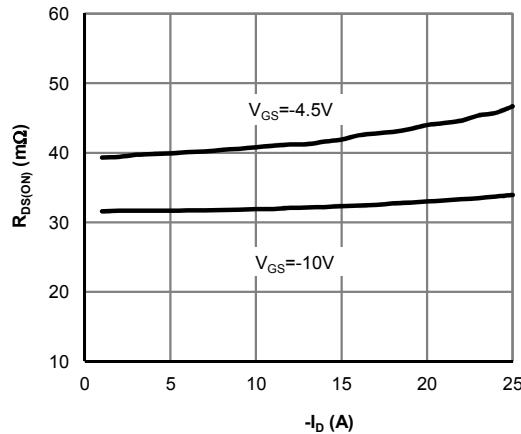
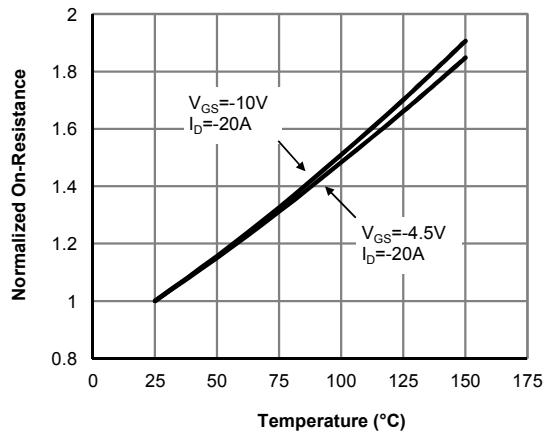
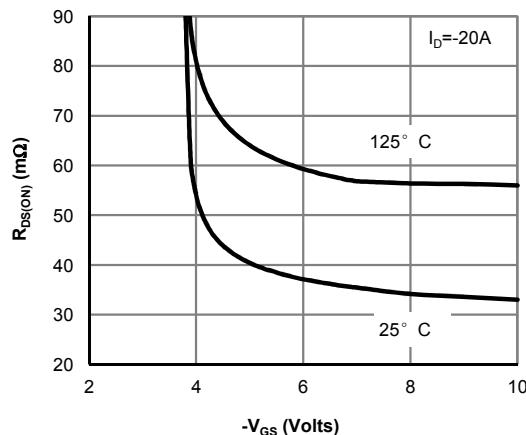
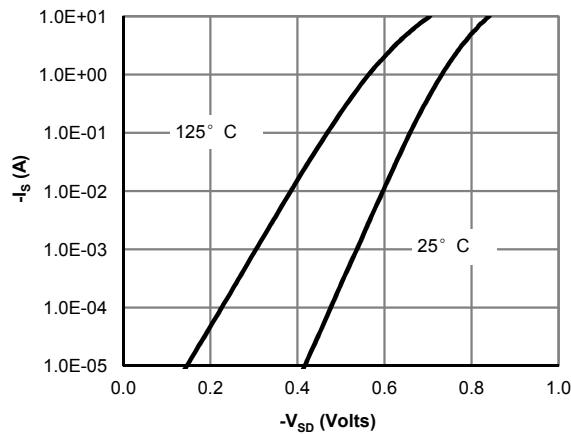
E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

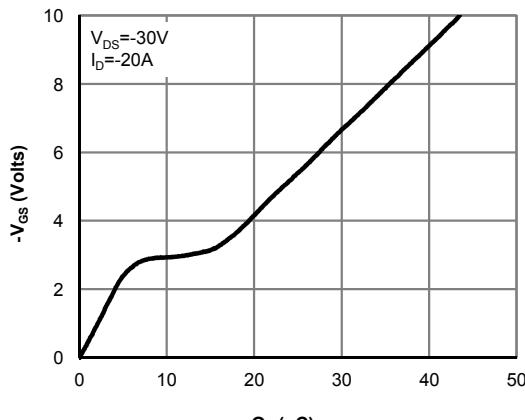
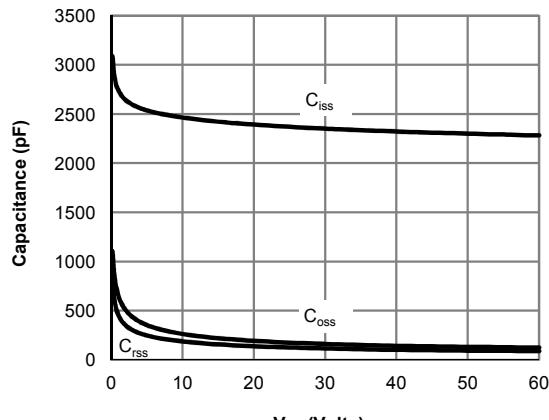
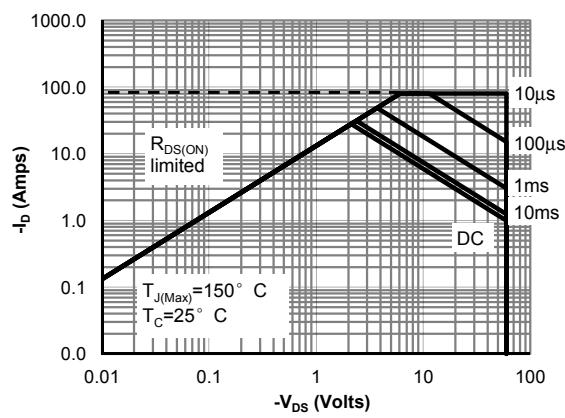
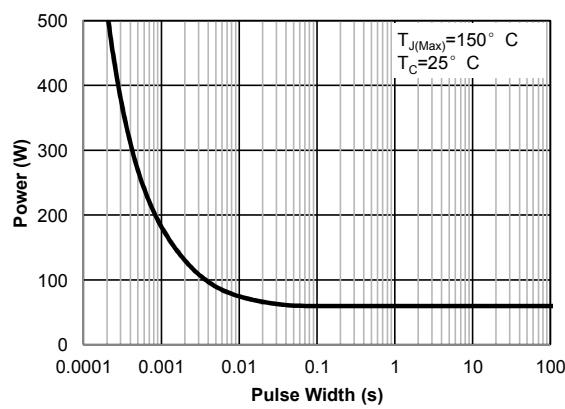
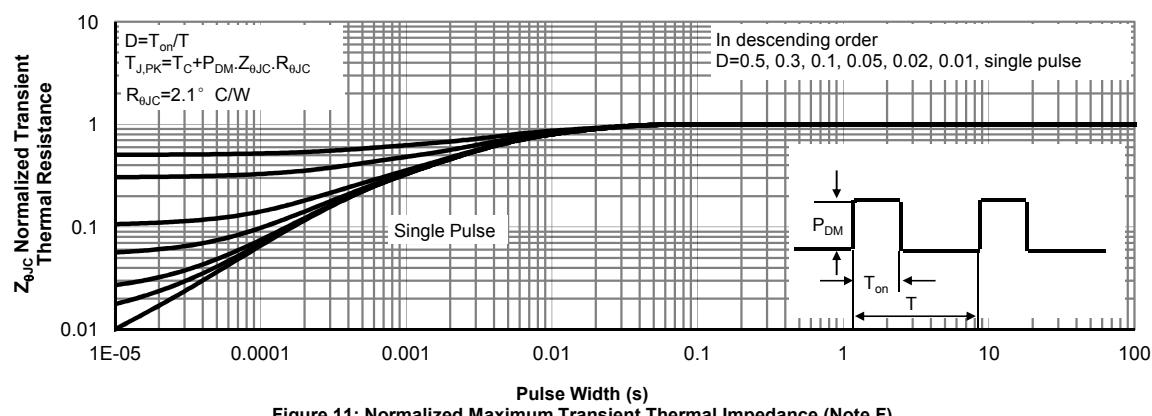
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

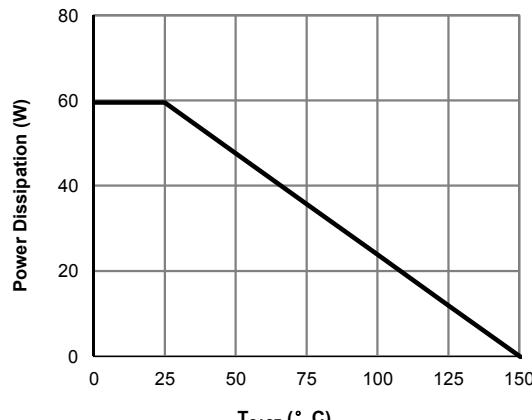
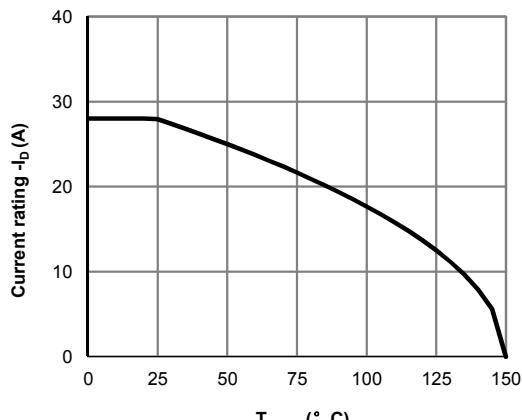
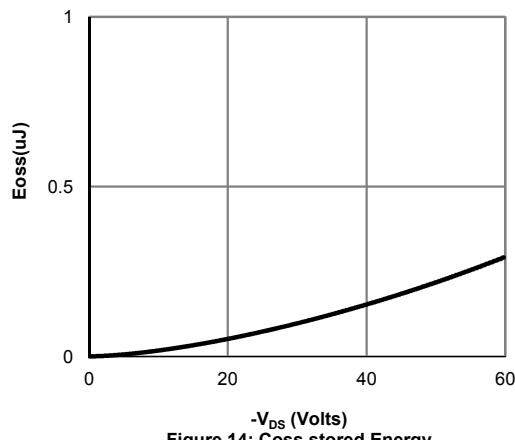
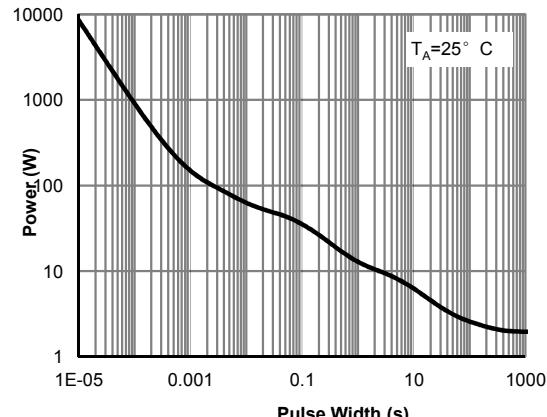
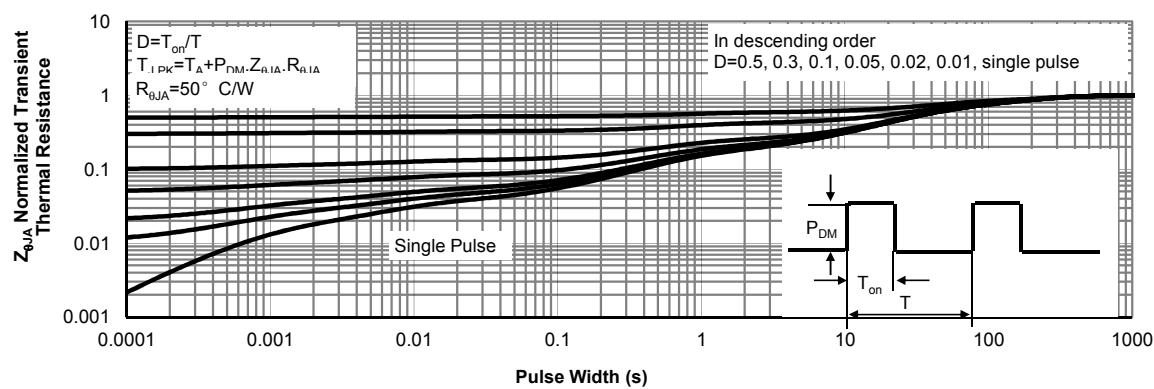
G. The maximum current rating is package limited.

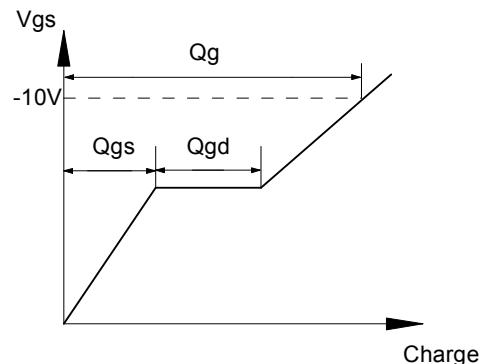
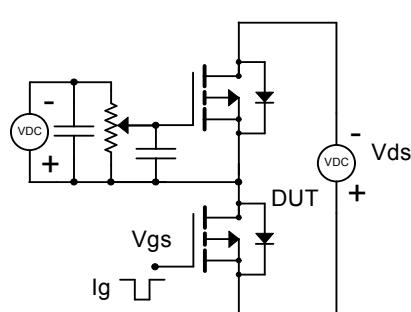
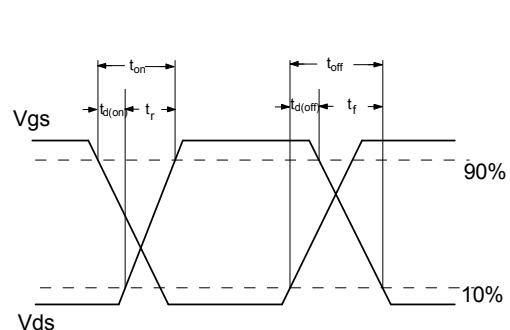
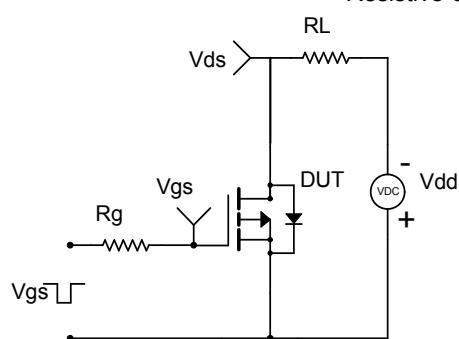
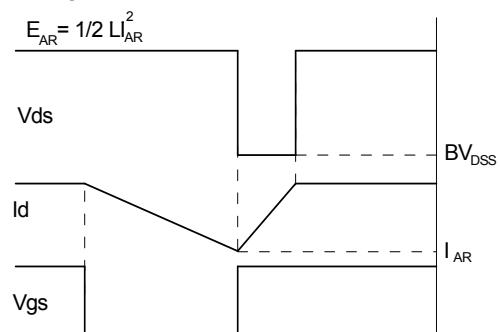
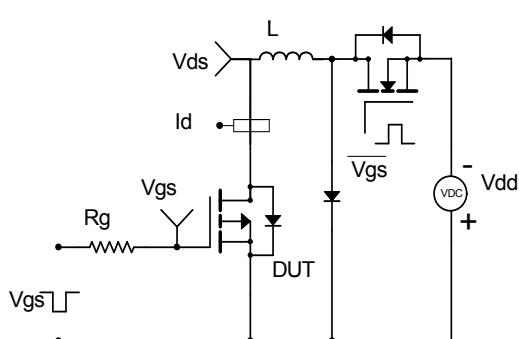
H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 12: Power De-rating (Note F)

Figure 13: Current De-rating (Note F)

Figure 14: Coss stored Energy

Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
